

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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		Examiner	Art Unit	Page 1 of 1
		Sara W. Crane	2811	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	B	US-6,706,402	03-2004	Rueckes et al.	428/408
X	C	US-6,314,019	11-2001	Kuekes et al.	365/151
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.